<u>\</u>						Sheet 1 c
Form PTO-1 (Rev. 8-83)		nt of Commerce rademark Office	Atty Docket 0756.		Serial No. 09	9/837,552
IN	NFORMATION DISCLOSURE STATEM	IENT	Applicants: Hisashi OHTA	NI et al.		· · · · · · · · · · · · · · · · · · ·
			Filing Date: April 19, 2001	4*	Group Art U	J nit:
	ι	J.S. PATENT	DOCUMENTS		0.1400.g.10 4	
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate
my PF	JC1>> 4,748,485	05/31/1988	Vasudev			Ситриорили
Mo	加	12/11/1990	Okamoto et al.	++		
www.	4,984,033	01/08/1991	Ishizu et al.			†
NOT W	4,996,575 5,034,788	02/26/1991	Ipri et al.			
NU AN	NT & TRANS	07/23/1991	Kerr			
HOL	5,103,277	04/07/1992	Caviglia et al.			
par	5,124,769	06/23/1992	Tanaka et al.			
400	5,140,391	08/18/1992	Hayashi et al.			
M	5,185,535	02/09/1993	Farb et al.			-
m	5,198,379	03/30/1993	Adan			1
NA	5,233,211	08/03/1993	Hayashi et al.			
NOR	5,246,882	09/21/1993	Hartmann			
Na	5,273,921	12/28/1993	Neudeck et al.			
NOR	5,275,972	01/04/1994	Ogawa et al.			
MUN	5,281,840	01/25/1994	Sarma	1 1		
MOR	5,294,821	03/15/1994	Iwamatsu			
hU-	5,327,001	07/05/1994	Wakai et al.			
HUN	5,359,219	10/25/1994	Hwang			
HOR	5,371,398	12/06/1994	Nishihara	1. 1		
700	5,420,048	05/30/1995	Kondo			
NO	5,470,793	11/28/1995	Kalnitsky			
MOL	5,475,238	12/12/1995	Hamada			
202	5,506,436	04/09/1996	Hayashi et al.			
700	5,580,802	12/03/1996	Mayer et al.			
hov	5,604,368	02/18/1997	Taur et al.			
אטט	5,807,772	09/15/1998	Takemura	1 (
NDN	5,818,076	10/06/1998	Zhang et al.			<u> </u>
M	5,917,221	06/29/1999	Takemura			
700	6,054,734	04/25/2000	Aozasa et al.			
un~	6,252,248	09/02/1986	Yamazaki Sano et al.			

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this formwith next communication to applicant.

Form PTO-1449 (Rev. 8-83)

Department of Commerce tent and Trademark Office

Atty Docket 0756-

Serial No. 09/837,552

INFORMATION DISCLOSURE STATEMENT

Applicants: Hisashi OHTANI et al.

Filing Date: April 19, 2001

Group Art Unit: Unassigned

FOREIGN PATENT DOCUMENTS

Examiner Initial P	Document Number	Date	Country	Class	Subclass \	<u>Translatio</u> Yes	on No
NOR.	0 178 447 01-059866 02-015676 02-666293 03-082171	04/23/1986	EP	11		Full Eng	
por is	3 01-059866	03/07/1989	JP			Eng Abst	
1/62 Ko	02-015676	01/19/1990	JP			Eng Abst	
NDEENT	TRA00 02-666293	06/27/1997	JP			Full Eng	
70°	03-082171	04/08/1991	JP			Eng Abst	
MU	03-256365	11/15/1991	JP			Eng Abst	
\20\	04-152574	05/26/1992	JP			Eng Abst	
201	04-364074	12/16/1992	JP			Eng Abst	
NOR	11-354802	12/24/1999	JP			Eng Abst	
NDR	2000-183356	06/30/2000	JP			Full Eng	
PUV	2000-194014	07/14/2000	JP			Full Eng	
M	2000-196093	07/14/2000	JP			Full Eng	
HOL	57-032641	02/22/1982	JP			Eng Abst	
HOR	58-115850	07/09/1983	JP			Full Eng	
NA	60-081869	05/09/1985	JP			Eng Abst	
HR	60-154660	08/14/1985	JP ·			Eng Abst	
ra.	61-067269	04/07/1986	JP ·			Eng Abst	
hor	61-088565	05/06/1986	JP /			Eng Abst	
hth)	61-220371	09/30/1986	JP			Eng Abst	
12h	62-005661	01/12/1987	JP			Eng Abst	
Mery	62-117359	05/28/1987	JP			Full Eng	
HON	64-019761	01/23/1989	JP			Eng Abst	
POR	64-053459	03/01/1989	JP			Full Eng	
200	64-053460	03/01/1989	JP			Full Eng	
ww	64-059866	03/07/1989	JP			Full Eng	
10A	93/21659	10/28/1993	wo			Full Eng	
L	• • • • • • • • • • • • • • • • • • • •					<u> </u>	L

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner Initial Farrah et al., "Analysis of Double-Gate Thin-Film Transistor", pp. 69-74, February 1967, IEEE Transactions on Electron Devices, Vol. ED-14, No. 2 02 Date Considered 🗸 Examiner

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this formwith next communication to applicant.

Form PTO-1 (Rev. 8-83)	449	Department of Commerce	Atty Docket 0756	Serial No. 09/837,552
IN	FORMATION DISCLO	OSURE STATEMENT	Applicants: Hisashi OHTANI et	al.
·	OIPE WIT		Filing Date: April 19, 2001	Group Art Unit:
	MIR 1 3 5001 55	OTHER DOCUMENTS	(Including Author, Title, Date, Pertinent F	G
Examiner Initial	Ishii et al., A Trial Pro			
hu.	Ishii et al., "A Trial Pro Physics, 2a-V-9	oduct of Dual-Gate MOS (X Mo	OS) Device", pp. 405, 1985, 46th	Japan Society of Applied
pa			sistors Using Lateral Solid-Phase Il of Applied Physics, Vol. 29, No.	
bor.	Noguchi et al., "Advar pp. 549-552, 1986, Ex Tokyo, B-10-2	nced High Mobility Polysilicon Standed Abstracts of the 18th I	Super-thin Film Transistor (SFT) nternational Conference on Solid	Using Solid Phase Growth", I State Devices and Materials,
por	Hayashi et al., "Polysi of Applied Physics, Vo		or (SFT)", pp. L819-L820, Noven	nber 1984, Japanese Journal
por			ansistor (SFT) with Twin Gates", vices and Materials, Tokyo, A-3-5	
400 /		•	stor", pp. 44-49, 1986, Semicono	
400	Vol. EDL-3, No. 12		", pp. 357-359, December 1982,	
hou	Specifications and Dra April 19, 2001, Shunp		Serial No. 09/837,877, "Semicono	ductor Device", Filing Date:
NON			Serial No. 09/837,558, "Semicono 9, 2001, Shunpei YAMAZAKI et a	
			: '	
•				
			,	
			• /	
•				
	1 0			
Fyaminer #	129-828	/ 1	Date Considered 10/1/03	
		sidered, whether or not citation is	in conformance with MPEP 609; D	raw line through citation if
		d. Include copy of this formwith		

08/13/2001

PTO/SB/08A (08-00) Approved for use through 10/31/2002. OMB 0651-0031

Under the Paperwork Reduction Act of 1995, no persons are required to export a collection of information unless it contains a valid OMB control number.

Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Complete if Known			
				Application Number	09/837,552		
				Filing Date	April 19, 2001		
				First Named Inventor	Hisashi OHTANI et al.		
(use as many sheets as necessary)				Group Art Unit	Unassigned		
				Examiner Name	Unassigned		
Sheet	1	of	1	Attorney Docket Number	0756-2296		

			U.S. PATENT DOCUMENT	S	
Examiner Initials*	Cite No.1	U.S. Patent Document	Name of Patentee or Applicant of Cited	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number Kind Code ² (if known)	Document		
por		4,609,930	Tsuneo YAMAZAKI et al.	09/02/1986	
	/				
-					

				FC	REIGN PATENT DOC	UMENTS		
Examiner Initials	Cite No. 1	Office ³	Number ⁴	Kind Code' (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
							,	
	+							
			отні	ER PRIOR A	ART – NON PATENT LITE	RATURE DOCUMENTS		•
Examiner Initials	Cite No.				or (in CAPITAL LETTERS), t urnal, serial, symposium, catalo publisher, city and/or count	og, etc.)., date, page(s), volum		T ²
			/	11				
	1		7 \//					
Examiner	111	∠	1 ///	7	Da	ite a d		

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Considered

Burden Hour Statement: This form is estimated to take 2.0 hours to complete. Time will vary depending upon the needs of the individual case. Any comments on the amount of time you are required to complete this form should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, Washington, DC 20231.

Signature

¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

¹Unique citation designation number. ²Applicant is to place a check mark here if English language Translation is attached.